

General Description:

The GL6N40A4 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications.

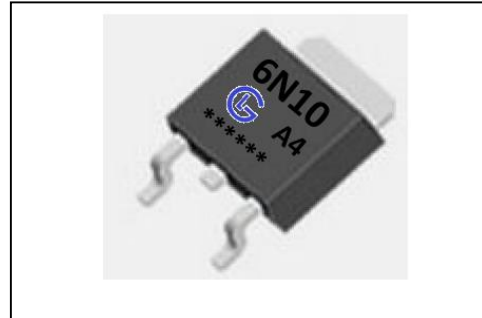
Features:

- VDS = 100V, ID = 6A RDS(ON) < 140mΩ @ VGS=10V (Typ:110mΩ)
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

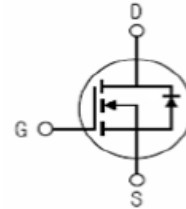
Applications:

Power switching application
Hard switched and high frequency circuits
Uninterruptible power supply

V _{DSS}	100	V
I _D	6	A
P _D	3	W
R _{DS(ON)type}	110	mΩ



Inner Equivalent Principium Chart



Absolute (T_c= 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V _{DSS}	Drain-to-Source Voltage	100	V
I _D	Continuous Drain Current	6	A
	Continuous Drain Current T _c =100 °C	3	A
I _{DM}	Pulsed Drain Current	24	A
V _{GS}	Gate-to-Source Voltage	± 20	V
P _D	Power Dissipation	3	W
T _J , T _{stg}	Operating Junction and Storage Temperature Range	-55 to 175	°C



GL6N10A4

GL Silicon N-Channel Power MOSFET

Electrical Characteristics (T_c= 25 °C unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	110	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =100V, V _{GS} =0V, T _a =25 °C	--	--	1	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+20V	--	--	1	μA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-20V	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =5A	--	110	140	mΩ
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.2	1.8	2.5	V
Pulse width t _p ≤ 380μs, δ ≤ 2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} =5V, I _D =2.9A	--	8	--	S
C _{iss}	Input Capacitance	V _{GS} =0V V _{DS} =25V f = 1.0MHz	--	690	--	pF
C _{oss}	Output Capacitance		--	120	--	
C _{rss}	Reverse Transfer Capacitance		--	90	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D =2A V _{DD} =30V V _{GS} =10V R _G =2.5Ω	--	11	--	ns
t _r	Rise Time		--	7.4	--	
t _{d(OFF)}	Turn-Off Delay Time		--	35	--	
t _f	Fall Time		--	9.1	--	
Q _g	Total Gate Charge	I _D =3A V _{DD} =30V V _{GS} =10V	--	15.5	--	nC
Q _{gs}	Gate to Source Charge		--	3.2	--	
Q _{gd}	Gate to Drain ("Miller") Charge		--	4.7	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	6	A
V_{SD}	Diode Forward Voltage	$I_S=6A, V_{GS}=0V$	--	--	1.2	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

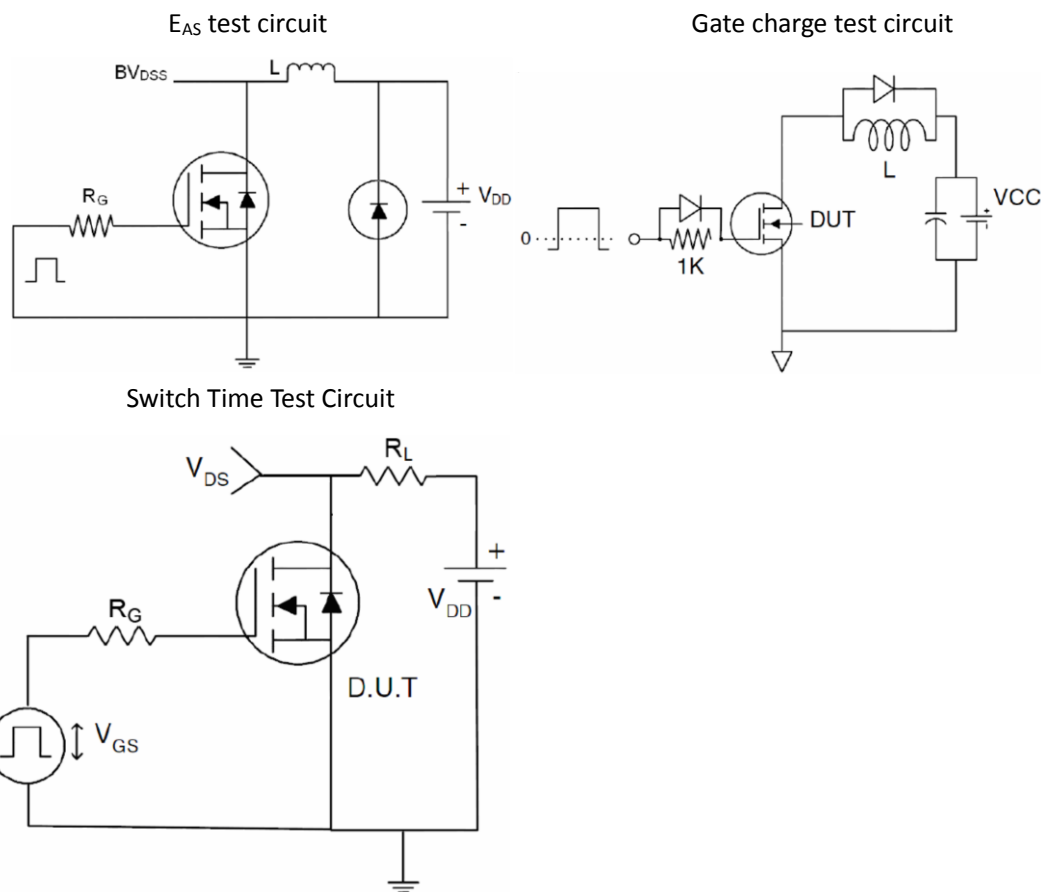
Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Junction-to-Ambient	41.7	$^{\circ}C/W$

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: EAS condition : $T_J=25^{\circ}C, V_{DD}=40V, V_G=10V, L=0.5mH, R_g=25\Omega$

^{a3}: $I_{SD}=6A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_J=25^{\circ}C$

Test Circuit



Typical Electrical and Thermal Characteristics (curves)

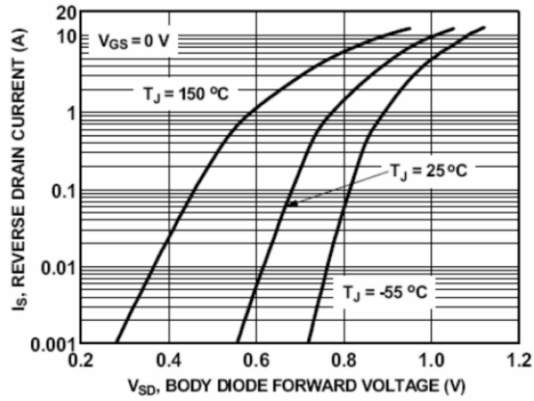


Figure1. Source-Drain Diode Forward Voltage

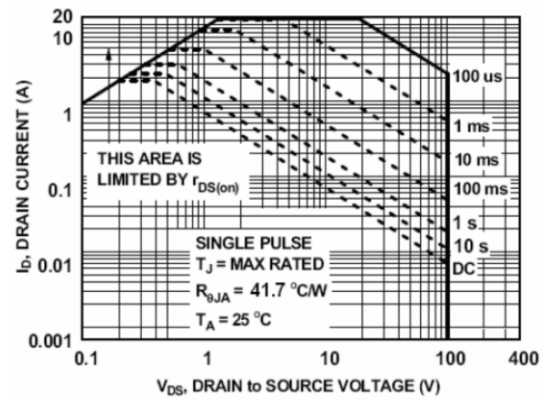


Figure2. Safe operating area

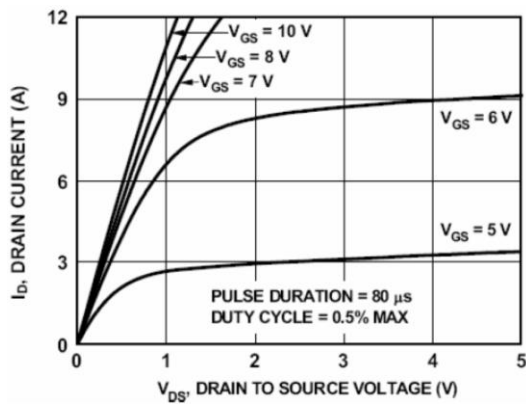


Figure3. Output characteristics

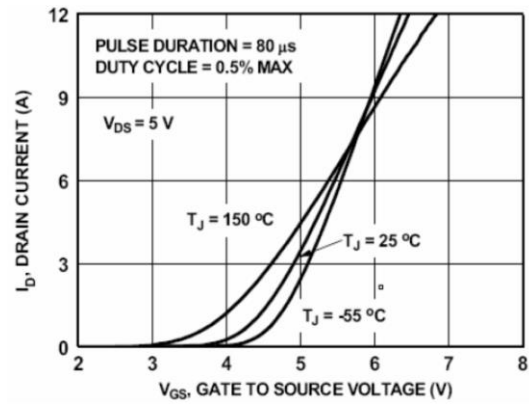
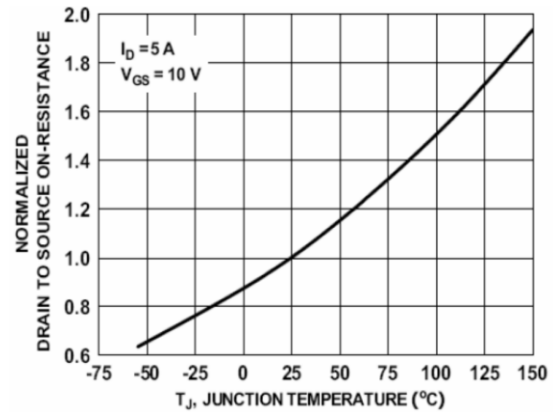
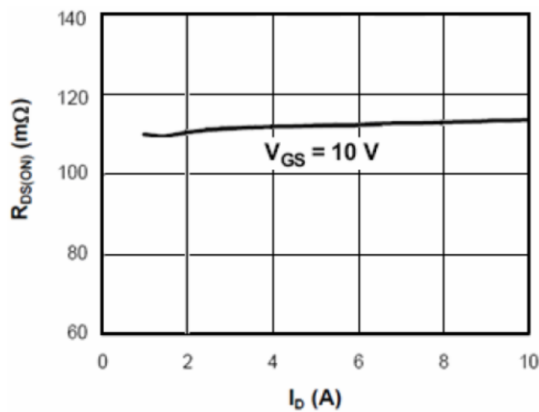


Figure4. Transfer characteristics



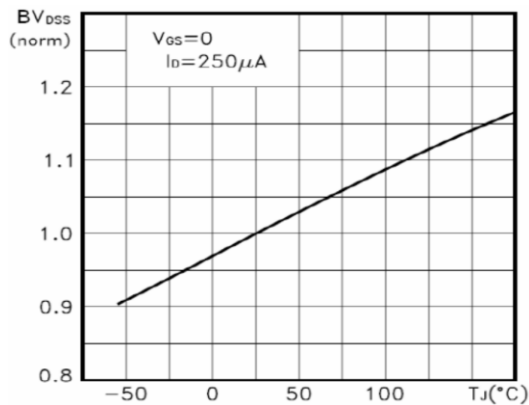


Figure7. BVDSS vs Junction Temperature

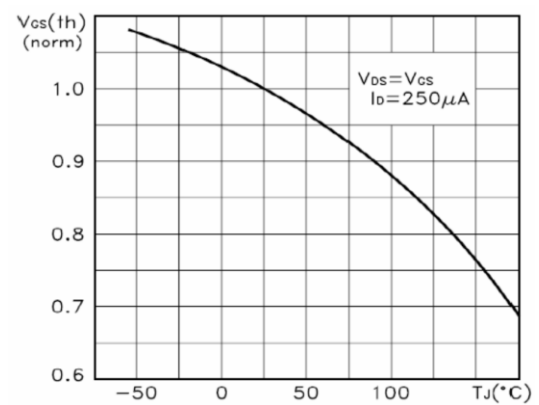


Figure8. VGS(th) vs Junction Temperature

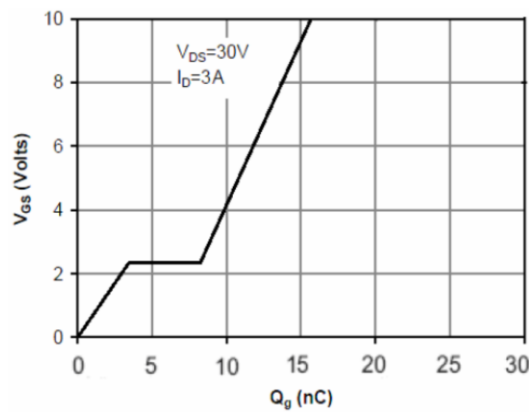


Figure9. Gate charge waveforms

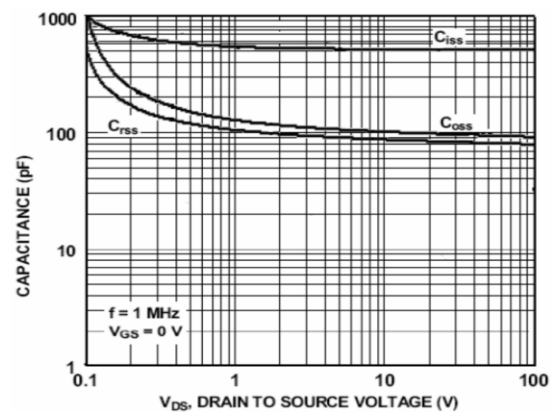


Figure10. Capacitance

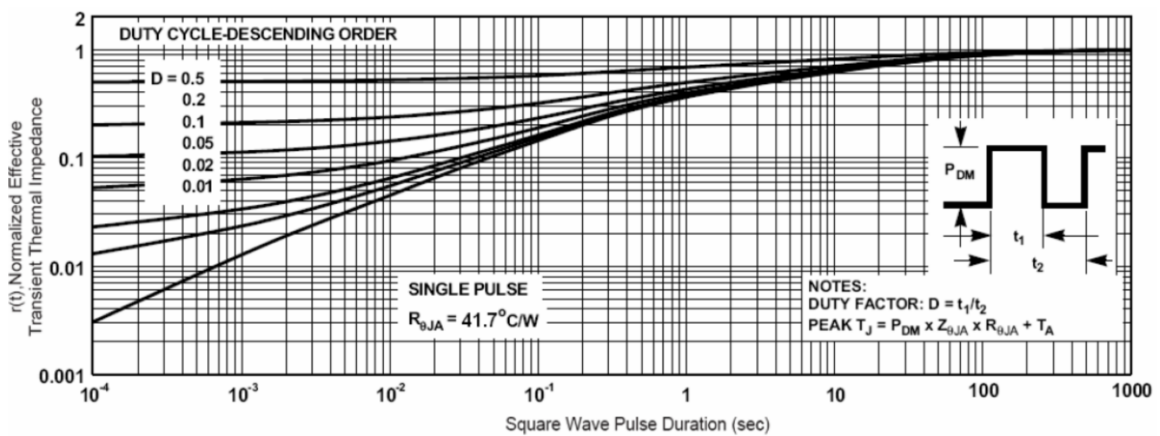


Figure11. Normalized Maximum Transient Thermal Impedance

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